Amendments to the claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (Original) A fluorometer for detecting intensity of fluorescence generated from a substance that is excited by light emitted from a light source,

wherein intensities P1, P2, ..., Pn of the fluorescence are detected respectively in n (n is an integer of not less than 2) limited wavelength regions $\lambda 1$, $\lambda 2$, ..., λn of the fluorescence.

- 2. (Original) The fluorometer according to claim 1, wherein a relative ratio or a difference between the detected intensities P1, P2, ..., Pn of the fluorescence is determined.
- 3. (Original) A fluorometer for detecting intensity of fluorescence generated from a substance that is excited by light emitted from a light source, comprising:

n (n is an integer of not less than 2) narrow-band-pass filters for transmitting light in different limited wavelength regions of the fluorescence, and

n light-receiving portions having one-to-one correspondence with the n narrow-band-pass filters,

wherein an intensity P1 of fluorescence transmitted through a first narrow-band-pass filter is detected by a first light-receiving portion, and

wherein fluorescence reflected from an (n-1)-th narrow-band-pass filter is allowed to enter an n-th narrow-band-pass filter, and an intensity Pn of fluorescence transmitted through the n-th narrow-band-pass filter is detected by an n-th light-receiving portion.

- 4. (Original) The fluorometer according to claim 3, wherein a relative ratio or a difference between the intensities P1, P2, ..., Pn of the fluorescence detected respectively by the n light-receiving portions is determined.
- 5. (Original) A fluorometer for detecting intensity of fluorescence generated from a substance that is excited by light emitted from a light source, comprising:

n (n is an integer of not less than 2) narrow-band reflection-type notch filters for reflecting light in different limited wavelength regions of the fluorescence, and

n light-receiving portions having one-to-one correspondence with the n narrow-band reflection-type notch filters,

wherein an intensity P1 of fluorescence reflected from a first narrow-band reflection-type notch filter is detected by a first light-receiving portion, and

wherein fluorescence transmitted through an (n-1)-th narrow-band reflection-type notch filter is allowed to enter an n-th narrow-band reflection-type notch filter, and an intensity Pn of fluorescence reflected from the n-th narrow-band reflection-type notch filter is detected by an n-th light-receiving portion.

6. (Original) The fluorometer according to claim 5, wherein the narrow-band reflection-type notch filter comprises a pair of glass substrates and a photopolymer arranged between the pair of glass substrates, and a periodic change in refractive index of the photopolymer occurs in its thickness direction.

- 7. (Original) The fluorometer according to claim 5, wherein a relative ratio or a difference between the intensities P1, P2, ..., Pn of the fluorescence detected respectively by the n light-receiving portions is determined.
- 8. (Currently Amended) The fluorometer according to any one of claims 1, 3, and 5 claim 1, wherein the light source is a light-emitting diode.
- 9. (Currently Amended) The fluorometer according to any one of claims 1, 3, and 5 claim 1, wherein the light source is a wavelength-variable semiconductor laser.
- 10. (Currently Amended) The fluorometer according to any one of claims 1, 3, and 5 claim 1, wherein a rare-earth element is added to the substance.
- 11. (Currently Amended) The fluorometer according to any one of claims 1, 3, and 5 claim 1, wherein a wavelength width of a spectrum of the fluorescence generated from the substance is detected by comparing the detected intensities P1, P2, ..., Pn of the fluorescence.
- 12. (New) The fluorometer according to claim 3, wherein the light source is a light-emitting diode.
- 13. (New) The fluorometer according to claim 3, wherein the light source is a wavelength-variable semiconductor laser.

14. (New) The fluorometer according to claim 3, wherein a rare-earth element is added to the substance.

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- 15. (New) The fluorometer according to claim 3, wherein a wavelength width of a spectrum of the fluorescence generated from the substance is detected by comparing the detected intensities P1, P2, ..., Pn of the fluorescence.
 - 16. (New) The fluorometer according to claim 5, wherein the light source is a light-emitting diode.
 - 17. (New) The fluorometer according to claim 5, wherein the light source is a wavelength-variable semiconductor laser.
 - 18. (New) The fluorometer according to claim 5, wherein a rare-earth element is added to the substance.
 - 19. (New) The fluorometer according to claim 5, wherein a wavelength width of a spectrum of the fluorescence generated from the substance is detected by comparing the detected intensities P1, P2, ..., Pn of the fluorescence.